Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10812010	CHUNG ET AL.	
Examiner	Art Unit	
Wendmagegn, Girumsew	2621	

SEARCHED					
Class	Subclass	Date	Examiner		
386	95	12/17/2007	gw		
386	124	12/17/2007	gw		
386	125	12/17/2007	gw		

SEARCH NOTES				
Search Notes	Date	Examiner		
US-PGPUB;USPAT;USOCR;EPO;JPO;DERWENT;IBM_TDB	12/17/2007	gw		
Consulted Thai Tran	12/17/2007	gw		
Inventor(s) search	12/17/2007	gw		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examine		

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